

Notice of References Cited	Application/Control No. 10/561,830	Applicant(s)/Patent Under Reexamination HAYASHI ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0110085	06-2004	Iwai et al.	430/270.1
*	B	US-2004/0029037	02-2004	Kamabuchi et al.	430/270.1
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2003167347 A	06-2003	Japan	HANEDA et al.	
	O					
	P					
	Q					
	R					
	S					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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